

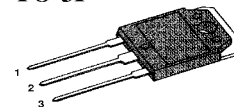
FEATURES

- Avalanche Rugged Technology
- Rugged Gate Oxide Technology
- Lower Input Capacitance
- Improved Gate Charge
- Extended Safe Operating Area
- Lower Leakage Current : 25 μ A (Max.) @ $V_{DS} = 600V$
- Low $R_{DS(ON)}$: 0.646 Ω (Typ.)

$$BV_{DSS} = 600 V$$

$$R_{DS(on)} = 0.8 \Omega$$

$$I_D = 10 A$$

TO-3P

1.Gate 2. Drain 3. Source

Absolute Maximum Ratings

Symbol	Characteristic	Value	Units
V_{DSS}	Drain-to-Source Voltage	600	V
I_D	Continuous Drain Current ($T_C=25^\circ C$)	10	A
	Continuous Drain Current ($T_C=100^\circ C$)	6.3	
I_{DM}	Drain Current-Pulsed ①	40	A
V_{GS}	Gate-to-Source Voltage	± 30	V
E_{AS}	Single Pulsed Avalanche Energy ②	545	mJ
I_{AR}	Avalanche Current ①	10	A
E_{AR}	Repetitive Avalanche Energy ①	19.3	mJ
dv/dt	Peak Diode Recovery dv/dt ③	3.0	V/ns
P_D	Total Power Dissipation ($T_C=25^\circ C$)	193	W
	Linear Derating Factor	1.54	
T_J, T_{STG}	Operating Junction and Storage Temperature Range	- 55 to +150	$^\circ C$
T_L	Maximum Lead Temp. for Soldering Purposes, 1/8 " from case for 5-seconds	300	

Thermal Resistance

Symbol	Characteristic	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	--	0.65	$^\circ C / W$
$R_{\theta CS}$	Case-to-Sink	0.24	--	
$R_{\theta JA}$	Junction-to-Ambient	--	40	

SSH10N60A

N-CHANNEL
POWER MOSFET

Electrical Characteristics ($T_C=25^\circ\text{C}$ unless otherwise specified)

Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Condition
BV_{DSS}	Drain-Source Breakdown Voltage	600	--	--	V	$V_{GS}=0V, I_D=250\mu A$
$\Delta BV/\Delta T_J$	Breakdown Voltage Temp. Coeff.	--	0.66	--	V/ $^\circ\text{C}$	$I_D=250\mu A$ See Fig 7
$V_{GS(th)}$	Gate Threshold Voltage	2.0	--	4.0	V	$V_{DS}=5V, I_D=250\mu A$
I_{GSS}	Gate-Source Leakage, Forward	--	--	100	nA	$V_{GS}=30V$
	Gate-Source Leakage, Reverse	--	--	-100	nA	$V_{GS}=-30V$
I_{DSS}	Drain-to-Source Leakage Current	--	--	25	μA	$V_{DS}=600V$
		--	--	250	μA	$V_{DS}=480V, T_C=125^\circ\text{C}$
$R_{DS(on)}$	Static Drain-Source On-State Resistance	--	--	0.8	Ω	$V_{GS}=10V, I_D=5A$ ④
g_{fs}	Forward Transconductance	--	8.5	--	Ω	$V_{DS}=50V, I_D=5A$ ④
C_{iss}	Input Capacitance	--	1750	2270	pF	$V_{GS}=0V, V_{DS}=25V, f=1\text{MHz}$ See Fig 5
C_{oss}	Output Capacitance	--	190	220		
C_{rss}	Reverse Transfer Capacitance	--	78	90		
$t_{d(on)}$	Turn-On Delay Time	--	20	50	ns	$V_{DD}=300V, I_D=10A,$ $R_G=6.2\Omega$ See Fig 13 ④ ⑤
t_r	Rise Time	--	23	55		
$t_{d(off)}$	Turn-Off Delay Time	--	85	180		
t_f	Fall Time	--	30	70		
Q_g	Total Gate Charge	--	74	95	nC	$V_{DS}=480V, V_{GS}=10V,$ $I_D=10A$ See Fig 6 & Fig 12 ④ ⑤
Q_{gs}	Gate-Source Charge	--	12	--		
Q_{gd}	Gate-Drain("Miller ") Charge	--	35.4	--		

Source-Drain Diode Ratings and Characteristics

Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Condition
I_S	Continuous Source Current	--	--	10	A	Integral reverse pn-diode in the MOSFET
I_{SM}	Pulsed-Source Current ①	--	--	40		
V_{SD}	Diode Forward Voltage ④	--	--	1.4	V	$T_J=25^\circ\text{C}, I_S=10A, V_{GS}=0V$
t_{rr}	Reverse Recovery Time	--	440	--	ns	$T_J=25^\circ\text{C}, I_F=10A$
Q_{rr}	Reverse Recovery Charge	--	4.7	--	μC	$di_F/dt=100A/\mu s$ ④

Notes ;

- ① Repetitive Rating : Pulse Width Limited by Maximum Junction Temperature
- ② $L=10mH, I_{AS}=10A, V_{DD}=50V, R_G=27\Omega, \text{Starting } T_J=25^\circ\text{C}$
- ③ $I_{SD} \leq 10A, di/dt \leq 50A/\mu s, V_{DD} \leq BV_{DSS}, \text{Starting } T_J=25^\circ\text{C}$
- ④ Pulse Test : Pulse Width = 250 μs , Duty Cycle $\leq 2\%$
- ⑤ Essentially Independent of Operating Temperature

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Fig 1. Output Characteristics

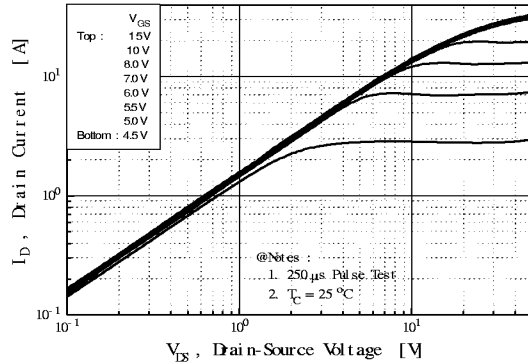


Fig 2. Transfer Characteristics

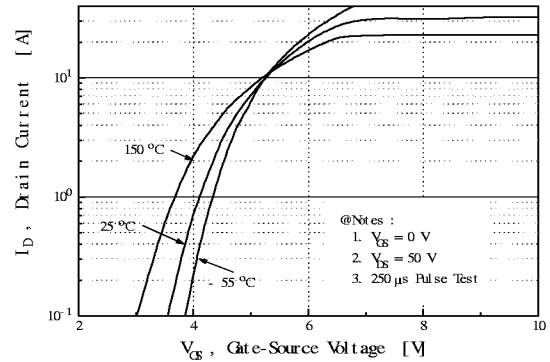


Fig 3. On-Resistance vs. Drain Current

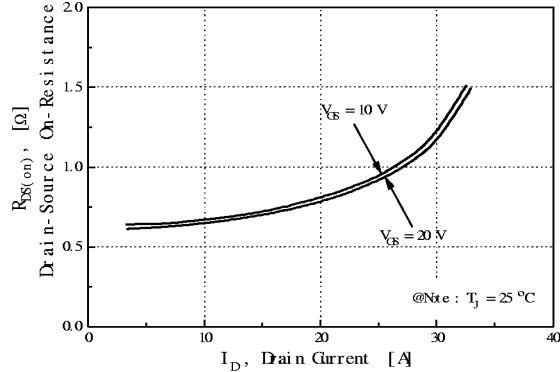


Fig 4. Source-Drain Diode Forward Voltage

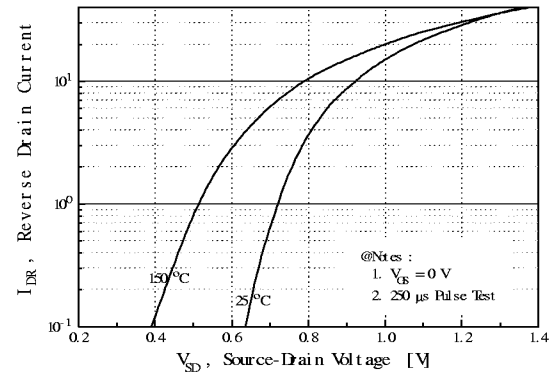


Fig 5. Capacitance vs. Drain-Source Voltage

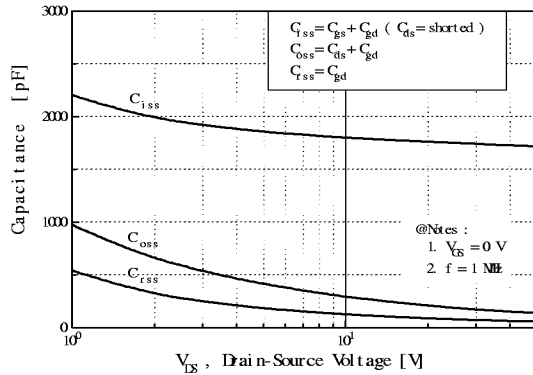
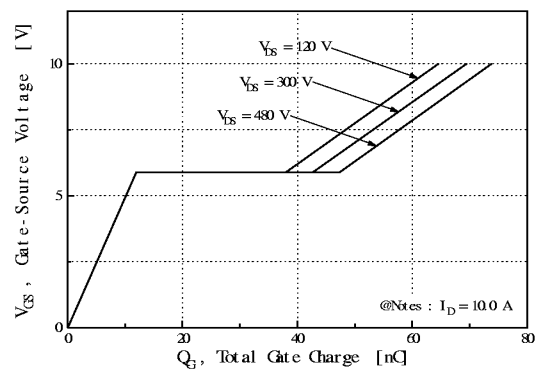
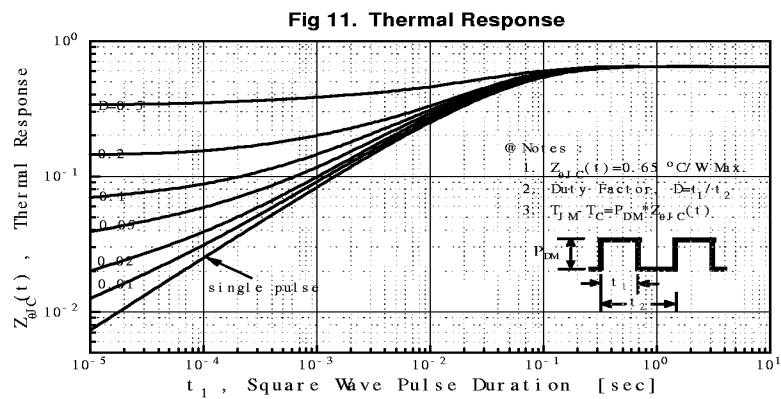
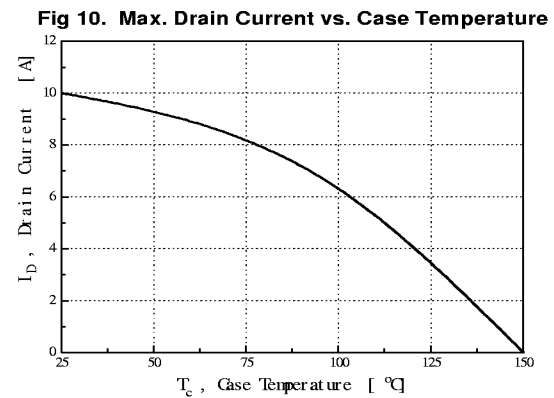
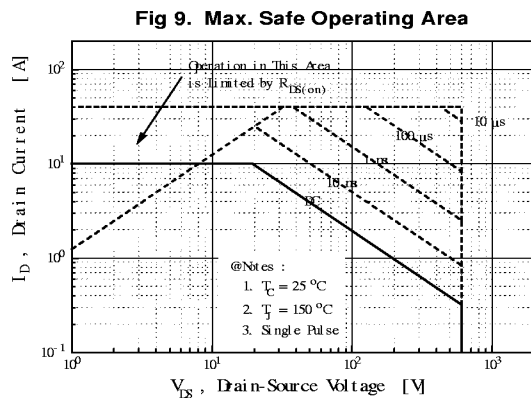
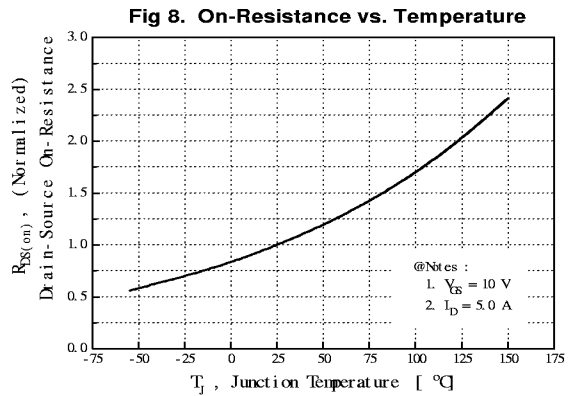
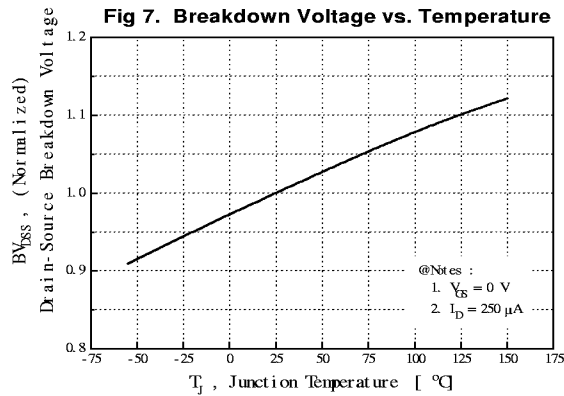


Fig 6. Gate Charge vs. Gate-Source Voltage



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N-CHANNEL POWER MOSFET



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Fig 12. Gate Charge Test Circuit & Waveform

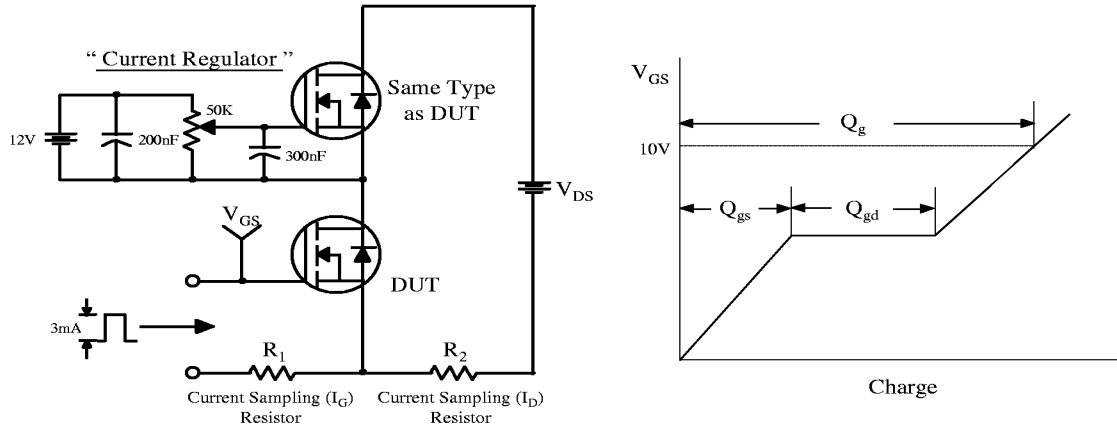


Fig 13. Resistive Switching Test Circuit & Waveforms

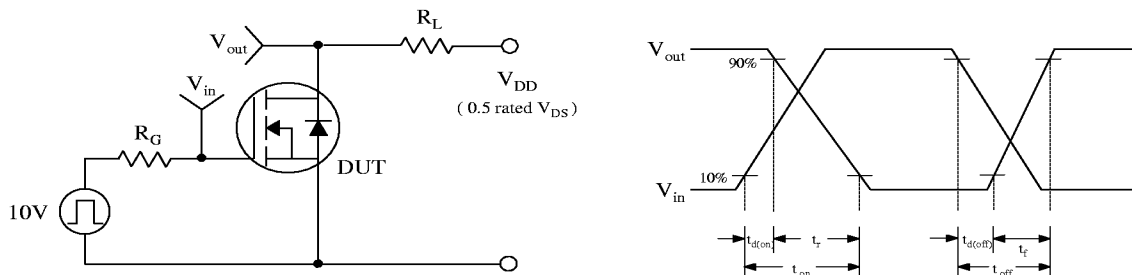


Fig 14. Unclamped Inductive Switching Test Circuit & Waveforms

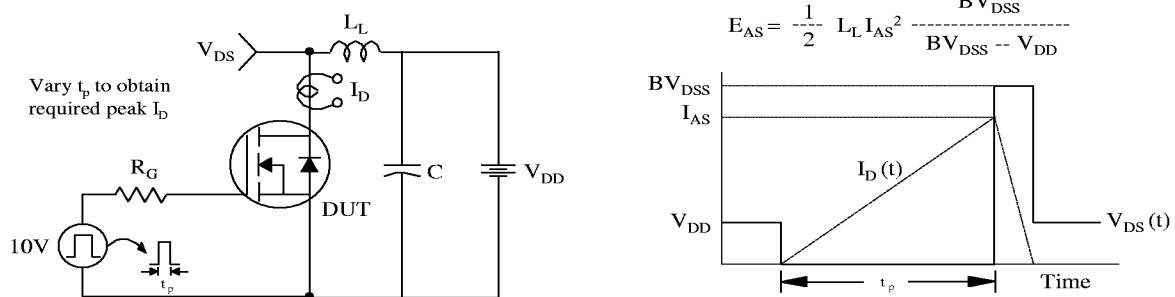


Fig 12. Gate Charge Test Circuit & Waveform

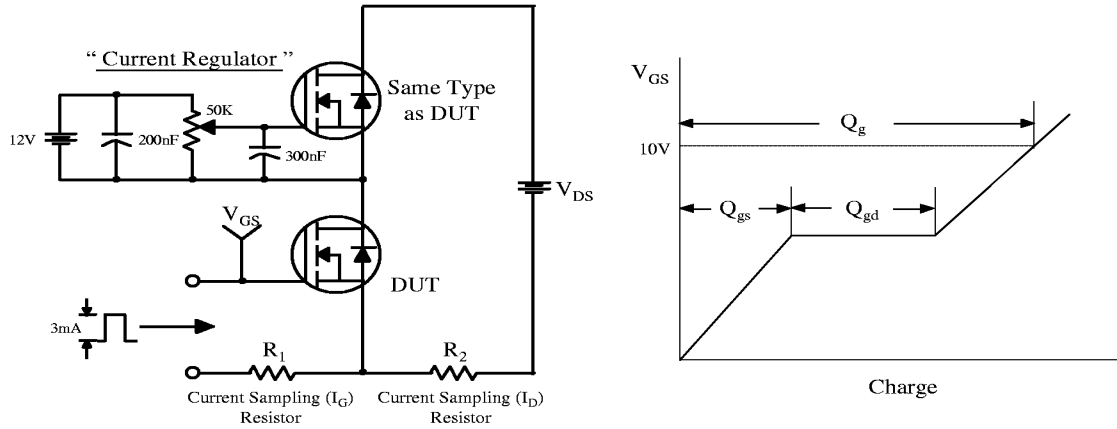


Fig 13. Resistive Switching Test Circuit & Waveforms

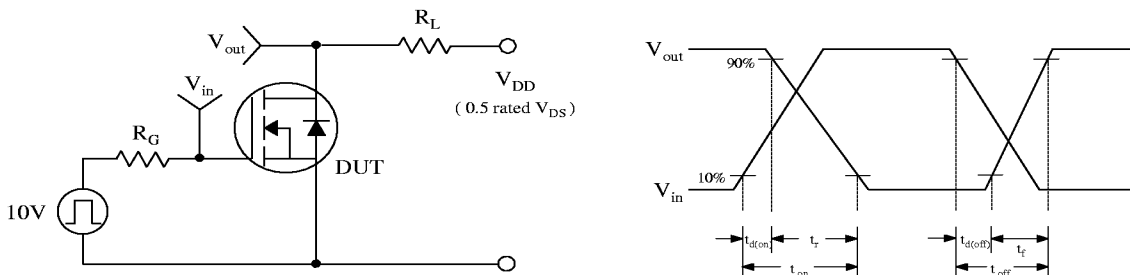


Fig 14. Unclamped Inductive Switching Test Circuit & Waveforms

